

Search Notes

Application/Control No.

10/777,680

Examiner

JASON L. LAZORCIK

Applicant(s)/Patent under
Reexamination

ETO ET AL.

Art Unit

1791

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|-----------------|-----------|----------|
| 065 | 30.13, 30.14 | 9/25/2006 | JLL |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|--|------------|------|
| Inventor Search: Nobuyuki Eto Hideki Isono | 9/25/2006 | JLL |
| Class Search (Key word limited) | 9/25/2006 | JLL |
| EAST Search (See Search History) | 9/25/2006 | JLL |
| Update EAST Search | 4/16/2007 | JLL |
| Updated EAST Search Substrate thickness 0.2-0.9mm | 10/29/2007 | JLL |
| Updated Search NPL searched for residual stress profile in chemically tempered glass. Note: engineered stress profile (ESP) | 8/17/2008 | JLL |
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